

# Search Notes



Application/Control No.

10/765,311

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

WENDELL ET AL.

Art Unit

2816

## SEARCHED

Class	Subclass	Date	Examiner
327	51	02.24.05	HAN
	55	T	T
365	189.04		
	189.05		
	189.06		
	189.09		
	189.11	↓	↓

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	02.24.05	HAN
See attachment		